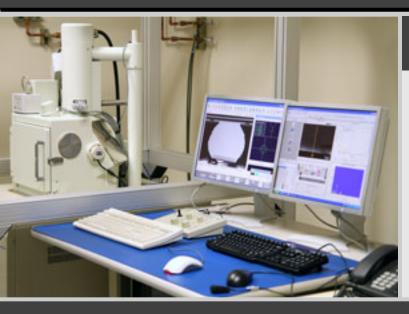


Scanning Electron Microscope



Features

- Resolution
 - High Vacuum mode: 3.0nm (30kV)
 - Low Vacuum mode: 4.0nm (30kV)
- Acceleration Voltage: 0.3 to 30kV
- Magnification: 5 to 300,000
- EMI cage for AC noise reduction
- Low vacuum mode for studying non-conductive samples
- Energy Dispersive Spectrum for Elemental Analysis (Qualitative and Quantitative)
- Elemental Mapping

Applications

- Surface morphology imaging for all types of sample including metals, ceramics, polymers, etc...
- Conductive and non-conductive samples
- Together with cross section grinding/polishing equipments, SEM is a perfect tool to detect defects such voids, cracks, delaminations, in IC components such as solder joints in PCBs.
- Elemental analysis and elemental mapping using energy dispersive spectrum technique (EDS) in all types of sample
- Effective measurement tool for thin films, intermetallic layers, Solder joint geometry etc